

TOSHIBA Transistor Silicon PNP Epitaxial Type

2SA2069

High-Speed Switching Applications
DC-DC Converter Applications

- High DC current gain: $h_{FE} = 200$ to 500 ($I_C = -0.15$ A)
- Low collector-emitter saturation voltage: $V_{CE(sat)} = -0.14$ V (max)
- High-speed switching: $t_f = 37$ ns (typ.)

Absolute Maximum Ratings ($T_a = 25^{\circ}\text{C}$)

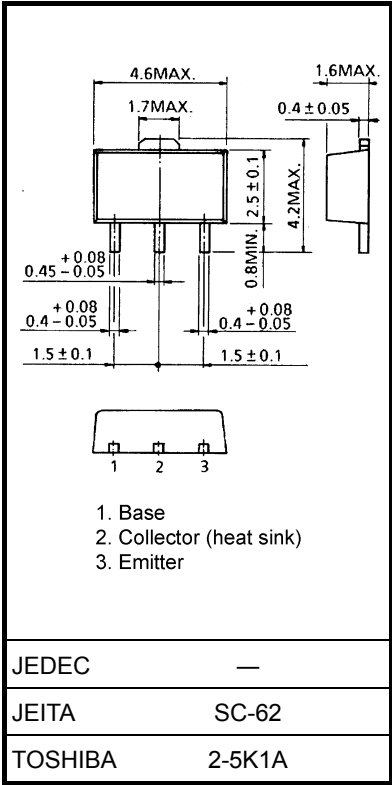
Characteristics		Symbol	Rating	Unit
Collector-base voltage		V_{CBO}	-20	V
Collector-emitter voltage		V_{CEO}	-20	V
Emitter-base voltage		V_{EBO}	-7	V
Collector current	DC	I_C	-1.5	A
	Pulse	I_{CP}	-2.5	
Base current		I_B	-150	mA
Collector power dissipation	$t = 10$ s	P_C	2.0	W
	DC	(Note 1)	1.0	
Junction temperature		T_j	150	$^{\circ}\text{C}$
Storage temperature range		T_{stg}	-55 to 150	$^{\circ}\text{C}$

Note 1: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm²)

Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Unit: mm



Weight: 0.05 g (typ.)

Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current		I_{CBO}	$V_{CB} = -20\text{ V}, I_E = 0$	—	—	-100	nA
Emitter cut-off current		I_{EBO}	$V_{EB} = -7\text{ V}, I_C = 0$	—	—	-100	nA
Collector-emitter breakdown voltage		$V_{(BR)\text{ CEO}}$	$I_C = -10\text{ mA}, I_B = 0$	-20	—	—	V
DC current gain		$h_{FE} (1)$	$V_{CE} = -2\text{ V}, I_C = -0.15\text{ A}$	200	—	500	
		$h_{FE} (2)$	$V_{CE} = -2\text{ V}, I_C = -0.5\text{ A}$	125	—	—	
Collector-emitter saturation voltage		$V_{CE (sat)}$	$I_C = -0.5\text{ A}, I_B = -17\text{ mA}$	—	—	-0.14	V
Base-emitter saturation voltage		$V_{BE (sat)}$	$I_C = -0.5\text{ A}, I_B = -17\text{ mA}$	—	—	-1.10	V
Collector output capacitance		C_{ob}	$V_{CB} = -10\text{ V}, I_E = 0, f = 1\text{ MHz}$	—	12	—	pF
Switching time	Rise time	t_r	See Figure 1. $V_{CC} \approx -10\text{ V}, R_L = 20\ \Omega$ $-I_{B1} = I_{B2} = -17\text{ mA}$	—	40	—	ns
	Storage time	t_{stg}		—	135	—	
	Fall time	t_f		—	37	—	

Marking

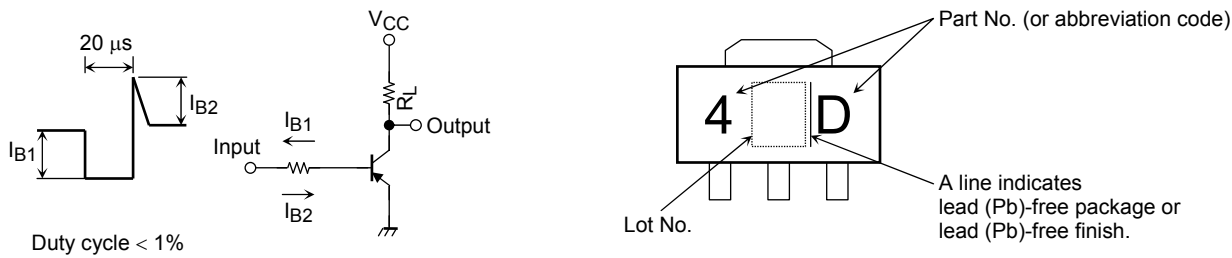
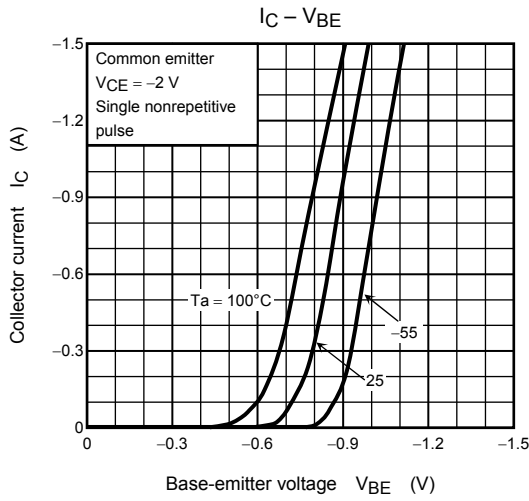
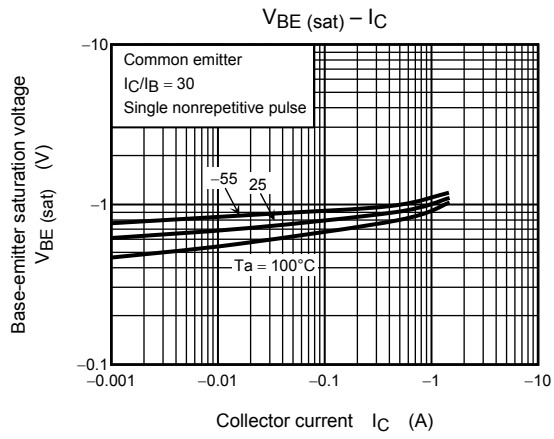
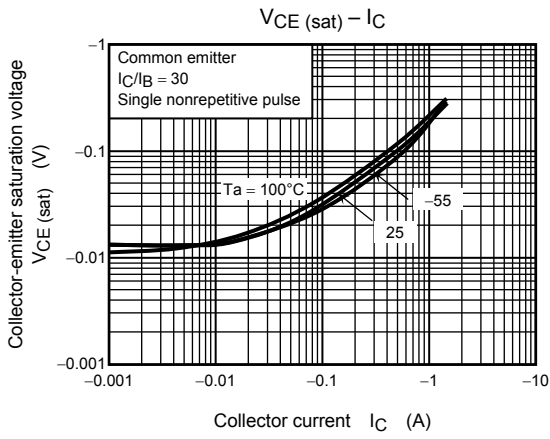
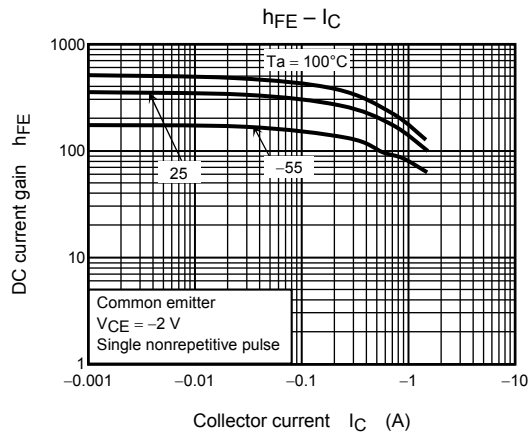
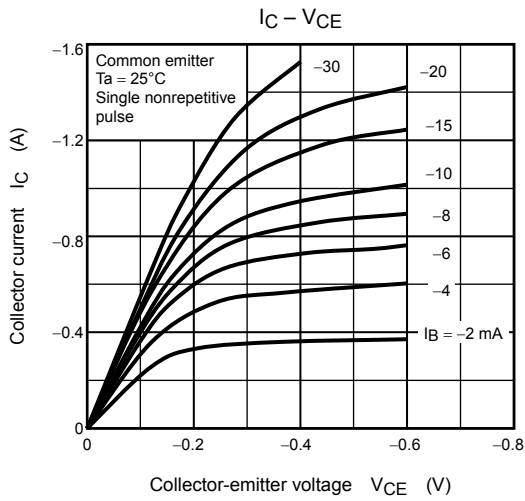
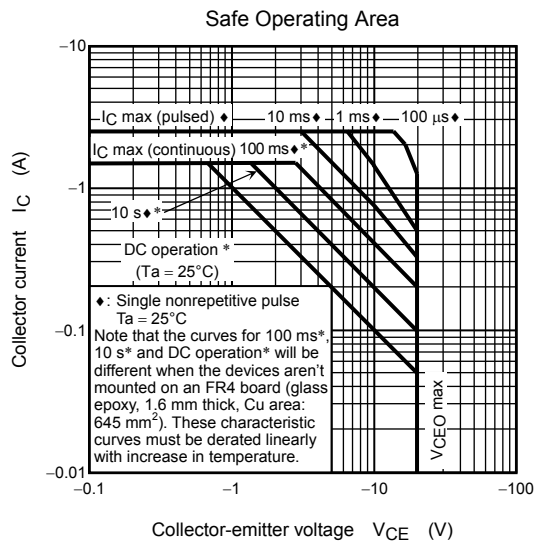
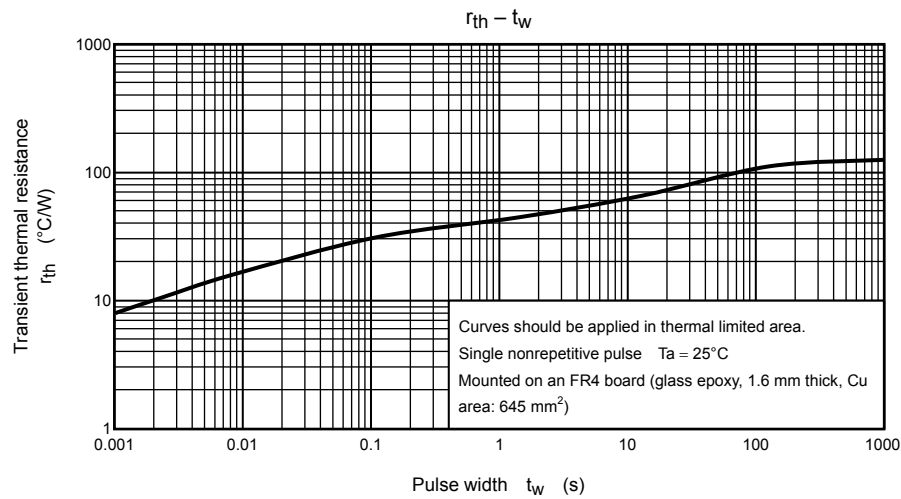


Figure 1 Switching Time Test Circuit & Timing Chart





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